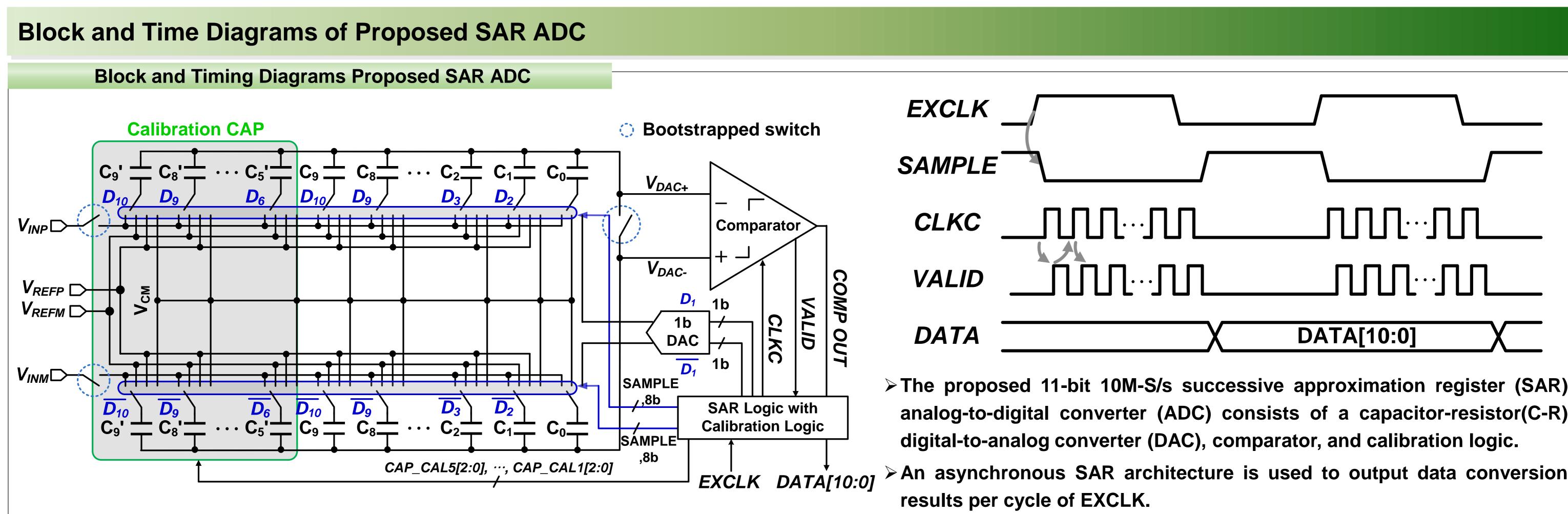


11-bit 10-MS/s SAR ADC with Capacitor Calibration for CDAC

Ho-Yong Jung, Eunji Youn and Young-Chan Jang

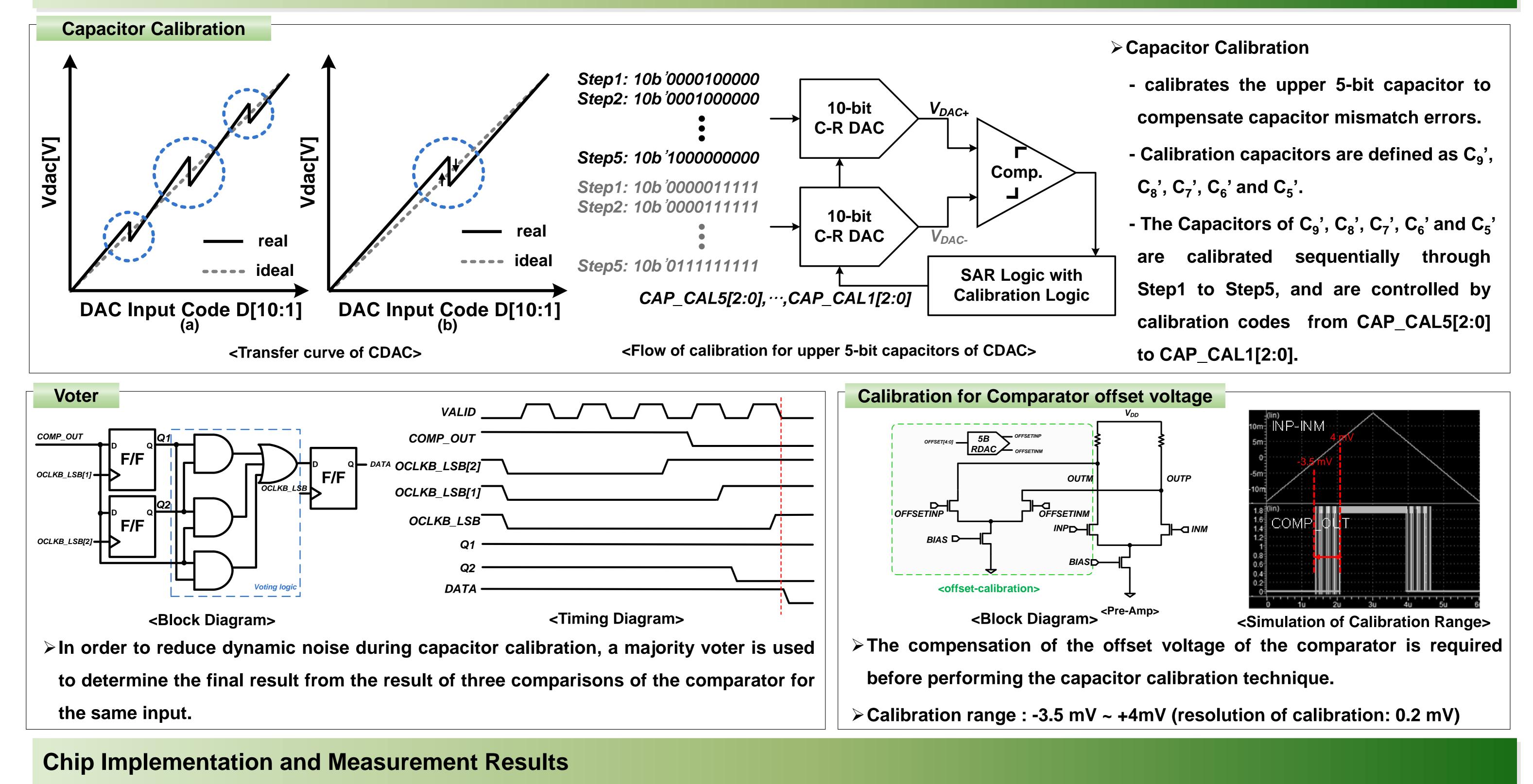
Department of Electronic Engineering, Kumoh National Institute of Technology, Gumi, Korea



> The proposed 11-bit 10M-S/s successive approximation register (SAR) analog-to-digital converter (ADC) consists of a capacitor-resistor(C-R)

>An asynchronous SAR architecture is used to output data conversion

Proposed Capacitor Calibration and Building Block

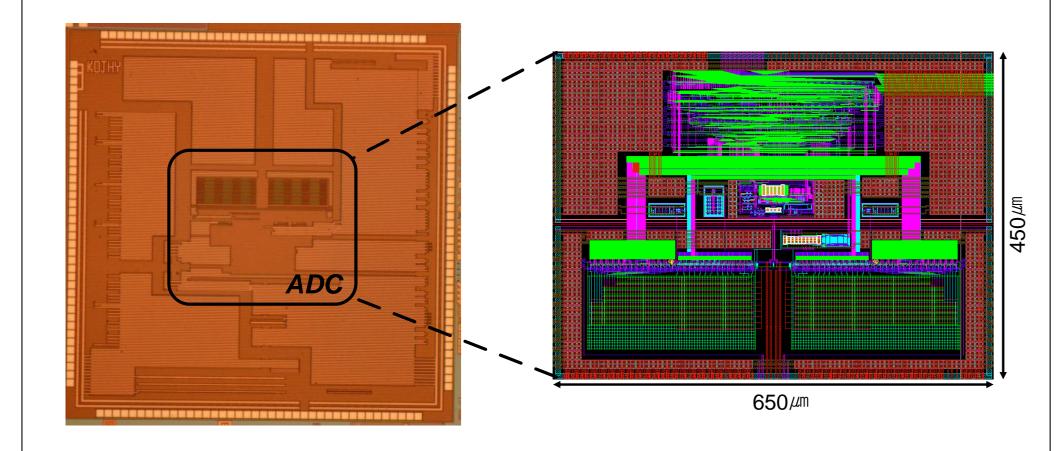


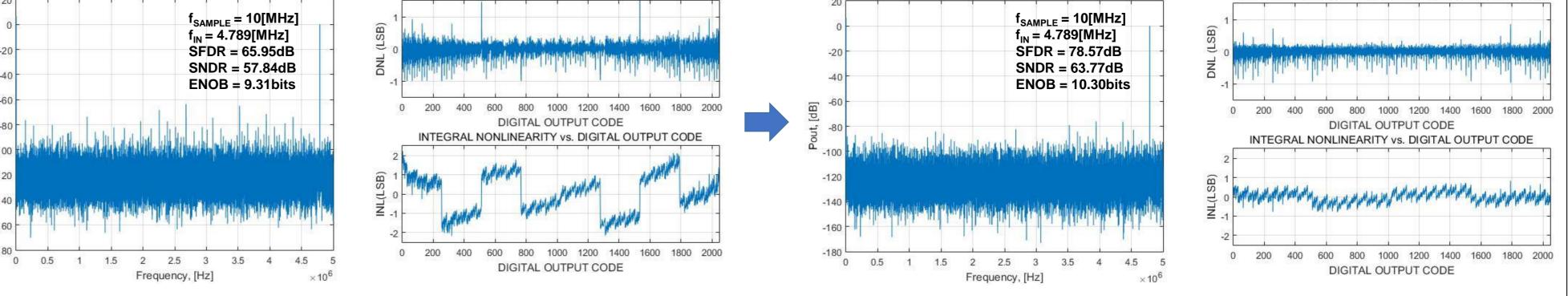
Chip Implementation

Measurement Results

DIFFERENTIAL NONLINEARITY vs. DIGITAL OUTPUT CODE

DIFFERENTIAL NONLINEARITY vs. DIGITAL OUTPUT CODE





<w/o capacitor calibration>

<w/ capacitor>

Proposed capacitor calibration used in the SAR ADC

- improves ENOB from 9.31 bits to 10.30 bits.

- improves DNL from -1/1.588 LSB to -0.975/0.855 LSB.

- improves INL from -2.171/2.227 LSB to -0.798/0.832 LSB.

Process & Supply: 180-nm 1-poly 5-metal CMOS process w/ MIM capacitor and 1.8V supply voltage \succ Power consumption: 583 μ \succ Core area: 650 μ m \times 450 μ m

※ This research was conducted using the MPW program and CAD tools supported by IC Design Education Center (IDEC).

